Notice of References Cited Application/Control No. 10/076,455 Examiner Hoan H. Tran Applicant(s)/Patent Under Reexamination YAMADA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,131,008	10-2000	Kanamori et al.	399/263
	В	US-6,266,505	07-2001	Ban et al.	399/258
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ŀ	US-			
	J	US-			
	К	US-			·
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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